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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/046,422	11/07/2001	Matthew A. Purdy	2000.082700	3477
23720	7590 02/22/2005	EXAMINER		
	S, MORGAN & AME	DUDA, KA	DUDA, KATHLEEN	
10333 RICHMOND, SUITE 1100 HOUSTON, TX 77042		•	ART UNIT	PAPER NUMBER
,			1756	

DATE MAILED: 02/22/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)				
		10/046,422	PURDY ET AL.				
Office Action Summary		Examiner	Art Unit				
		Kathleen Duda	1756				
Period fo	The MAILING DATE of this communication app			Idress			
A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely. - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication. - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).							
Status							
2a)⊠ 3)□	Since this application is in condition for allowa	s action is non-final. nce except for formal matters, pro		e merits is			
closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.							
Disposition of Claims 4) Claim(s) 1-29 and 42-54 is/are pending in the application.							
5)⊠ 6)⊠ 7)□	4a) Of the above claim(s) is/are withdrace Claim(s) 1-29 and 42-45 is/are allowed. Claim(s) 46-54 is/are rejected. Claim(s) is/are objected to. Claim(s) are subject to restriction and/or	•					
Application	on Papers						
9) The specification is objected to by the Examiner. 10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner. Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a). Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d). 11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.							
Priority u	nder 35 U.S.C. § 119						
12)	Acknowledgment is made of a claim for foreign All b) Some * c) None of: 1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority document application from the International Bureauee the attached detailed Office action for a list	s have been received. s have been received in Application of the second second in the second second in the second second in the second second in the second	on No ed in this National	Stage			
Attachment	(s)						
2) Notice 3) Inform	e of References Cited (PTO-892) e of Draftsperson's Patent Drawing Review (PTO-948) nation Disclosure Statement(s) (PTO-1449 or PTO/SB/08) No(s)/Mail Date	4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal P 6) Other:	ite	D-152)			

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DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.
- 2. Claims 46-54 are rejected under 35 U.S.C. 102(e) as being anticipated by Ling (US Patent 6,368,762).

Ling teaches the steps of the instant claims 1-29, in col.4; line.21-col.5; line.38. The steps comprise forming a process layer of an oxide on a wafer, forming a SiN layer, coating a photoresist layer, measuring the reflectance of the stack /SiN (fig.1) and adjusting the exposure level to the reflectivity of the layer. The measurement techniques are well known in the art and disclosed by Ling (5; 5-20). Note that Ling uses the SiN layer as a mask (4; 55); however the inherent ARC-property of the SiN layer is utilized by Ling as seen from the measurement of the reflectance of the layer.

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3. Claims 46-54 are rejected under 35 U.S.C. 102(e) as anticipated by Bhakta et al (US Pat. 6,482,573).

The applied reference has a common assignee with the instant application. Based upon the earlier effective U.S. filing date of the reference, it constitutes prior art under 35 U.S.C. 102(e). This rejection under 35 U.S.C. 102(e) might be overcome either by a showing under 37 CFR 1.132 that any invention disclosed but not claimed in the reference was derived from the inventor of this application and is thus not the invention "by another," or by an appropriate showing under 37 CFR 1.131.

The process steps of the independent claims are illustrated in fig.6 and disclosed in detail (4; 9-5; 22). It teaches conventional inclusion of an ARC layer between the polysilicon and the photoresist (3; 4-13). The averaging of the reflectivity is a well-known process control technique as argued above with reference to Ling.

4. Claims 46-54 are rejected under 35 U.S.C. 102(e) as being anticipated by Brown et al (US Pat.6,689,519).

Brown discloses a process control technique wherein the optical characteristics of a photoresist layer are determined and used to control (in a feed forward or feedback loop) exposure dose and post exposure bake (PEB) parameters (fig.1). The wafer stack obtained by the instant claimed

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process steps is disclosed (5; 31-6; 16). It teaches measurement of the optical properties of the stack by reflectometry, ellipsometry and the like (6; 25-59). The optical properties may be measured after the ARC coating (10; 54-62). The measurements are used to control the exposure dose or PEB process parameters (6; 56-7; 32).

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Response to Amendment

- 5. The 35 USC 103 rejection of the claims has been overcome due to the statement of common ownership made in Applicant's response on the bottom of page 16 which removes the references from a 35 USC 103 rejection.
- 6. The 35 USC 102(e) rejections of claims 1-29 have been overcome due to the amendments to the claims which specifically recite determining the index of refraction and extinction coefficient which is not taught by the prior art of record. These claims are allowed for these reasons. In addition, newly added claims 42-45 which are dependent on claims 1-29 are found to be allowable.

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7. Art rejections under 35 USC 102(e) have been made of newly added claims 46-54. These claims recite the broader recitation of "optical characteristics" which is taught by the art used in the rejections.

Conclusion

8. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

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9. Any inquiry concerning this communication should be directed to Examiner K. Duda at (571) 272-1383. Official FAX communications should be sent to (703) 872-9306.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Mark Huff, can be reached at 571-272-1385.

Information regarding the status of an application may be obtained from the Patent Application Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Kathleen Duda Primary Examiner Art Unit 1756